

# N-channel TrenchMOS intermediate level FET Rev. 3 — 18 January 2012

**Product data sheet** 

#### 1. **Product profile**

### 1.1 General description

Intermediate level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in high-performance automotive applications.

#### 1.2 Features and benefits

- AEC Q101 compliant
- High current handling capability, up to 320 A
- Low conduction losses due to very low on-state resistance

### **1.3 Applications**

- 12 V automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoids

### 1.4 Quick reference data

- Suitable for standard and logic level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

Table 1.	Quick reference data					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C	-	-	55	V
I <sub>D</sub>	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C};$ see <u>Figure 1</u>	-	-	228	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	-	300	W
Static cha	aracteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS}$ = 10 V; $I_D$ = 90 A; $T_j$ = 25 °C; see <u>Figure 11</u>	-	1.9	2.3	mΩ



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# BUK6C2R1-55C

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Quick reference data	continued				
Parameter	Conditions	Min	Тур	Max	Unit
characteristics					
gate-drain charge	I <sub>D</sub> = 180 A; V <sub>DS</sub> = 44 V; V <sub>GS</sub> = 10 V; see <u>Figure 13;</u> see <u>Figure 14</u>	-	79	-	nC
e ruggedness					
non-repetitive drain-source avalanche energy	$ \begin{split} & I_D = 120~A;~V_sup \leq 55~V; \\ & R_GS = 50~\Omega;~V_GS = 10~V; \\ & T_j(init) = 25~^\circC;~unclamped \end{split} $	-	-	770	mJ
	Parameter characteristics gate-drain charge e ruggedness non-repetitive drain-source	characteristicsgate-drain charge $I_D = 180 \text{ A}; V_{DS} = 44 \text{ V};$ $V_{GS} = 10 \text{ V};$ see Figure 13; see Figure 14e ruggednessnon-repetitive drain-source $I_D = 120 \text{ A}; \text{ V}_{sup} \le 55 \text{ V};$ $R_{GS} = 50 \Omega; \text{ V}_{GS} = 10 \text{ V};$	ParameterConditionsMincharacteristicsgate-drain chargeI_D = 180 A; V_{DS} = 44 V; $V_{GS} = 10 V;$ see Figure 13; see Figure 14-e ruggednessnon-repetitive drain-sourceI_D = 120 A; V_{sup} \le 55 V; $R_{GS} = 50 \Omega; V_{GS} = 10 V;$	ParameterConditionsMinTypcharacteristicsgate-drain chargeI_D = 180 A; V_{DS} = 44 V; $V_{GS} = 10 V;$ see Figure 13; see Figure 14-79e ruggednessnon-repetitive drain-sourceI_D = 120 A; V_{sup} \le 55 V; $R_{GS} = 50 \Omega; V_{GS} = 10 V;$	ParameterConditionsMinTypMaxcharacteristicsgate-drain charge $I_D = 180 \text{ A}; V_{DS} = 44 \text{ V};$ $V_{GS} = 10 \text{ V};$ see Figure 13; see Figure 14-79-e ruggednessnon-repetitive drain-source $I_D = 120 \text{ A}; V_{sup} \le 55 \text{ V};$ $R_{GS} = 50 \Omega; V_{GS} = 10 \text{ V};$ -770

## 2. Pinning information

Table 2.	Pinning	j information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	S	source	mb	
3	S	source		
4	D	drain <sup>[1]</sup>	i ii	
5	S	source		mbb076 S
6	S	source	123 567	
7	S	source	SOT427 (D2PAK)	
mb	D	mounting base; connected to drain		

[1] It is not possible to connect to pin 4 of the SOT427 package.

## 3. Ordering information

Table 3. Ordering	information		
Type number	Package		
	Name	Description	Version
BUK6C2R1-55C	D2PAK	plastic single-ended surface-mounted package (D2PAK); 7 leads (one lead cropped)	SOT427

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### 4. Limiting values

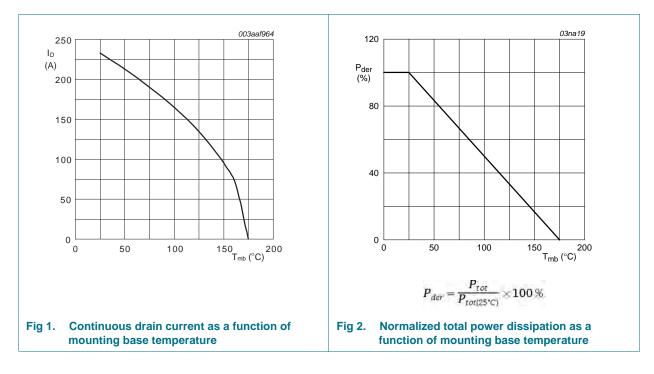
#### Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Мах	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C	-	55	V
V <sub>GS</sub>	gate-source voltage	Pulsed	<u>[1]</u> -20	20	V
		DC	<sup>[2]</sup> -16	16	V
I <sub>D</sub>	drain current	$T_{mb}$ = 25 °C; $V_{GS}$ = 10 V; see <u>Figure 1</u>	-	228	А
		T <sub>amb</sub> = 100 °C; V <sub>GS</sub> = 10 V; see <u>Figure 1</u>	-	162	A
I <sub>DM</sub>	peak drain current	T <sub>mb</sub> = 25 °C; pulsed; t <sub>p</sub> ≤ 10 μs; see <u>Figure 3</u>	-	914	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	300	W
T <sub>stg</sub>	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-drai	in diode				
Is	source current	T <sub>mb</sub> = 25 °C	-	228	А
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$	-	914	А
Avalanche I	ruggedness				
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 120 A; $V_{sup} \le 55$ V; $R_{GS} = 50$ Ω; $V_{GS} = 10$ V; $T_{j(init)} = 25$ °C; unclamped	-	770	mJ

[1] Accumulated pulse duration not to exceed 5mins.

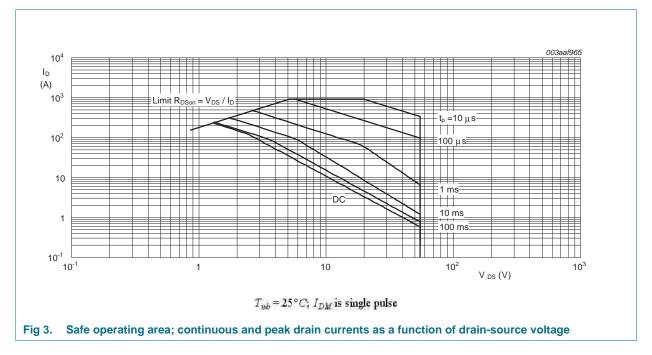
[2] -16V accumulated duration not to exceed 168 hrs.



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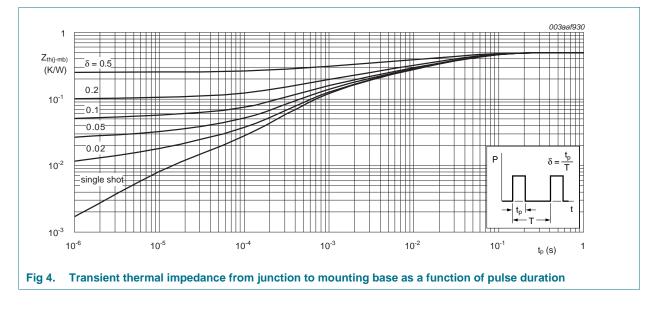
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### 5. Thermal characteristics

#### Table 5.Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see Figure 4	-	-	0.5	K/W



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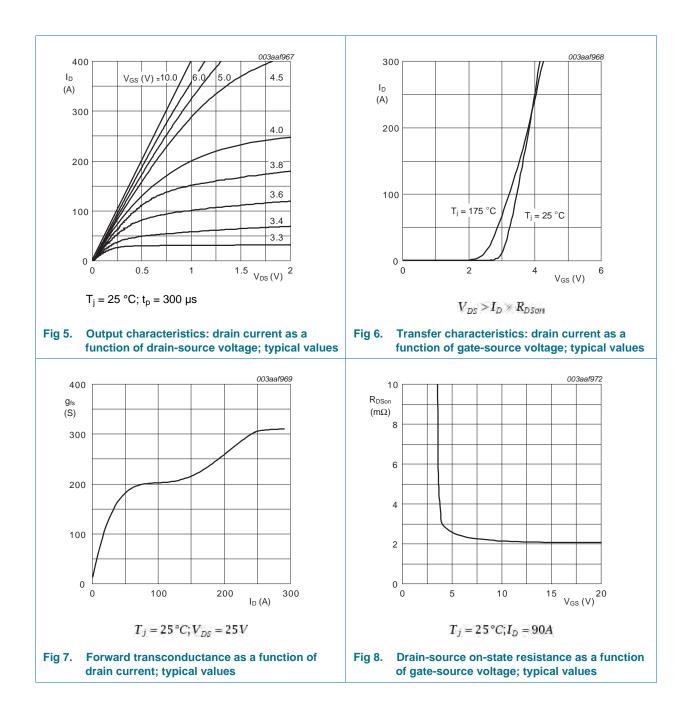
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### 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	octeristics					
V <sub>(BR)DSS</sub>	drain-source	I <sub>D</sub> = 250 μA; V <sub>GS</sub> = 0 V; T <sub>i</sub> = 25 °C	55	-	-	V
(2.1)200	breakdown voltage	$I_{\rm D} = 250 \ \mu \text{A}; \ V_{\rm GS} = 0 \ \text{V}; \ T_{\rm i} = -55 \ \text{°C}$	50	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see Figure 9; see Figure 10	1.8	2.3	2.8	V
V <sub>GSth</sub>	gate-source threshold voltage	$I_D = 2.5 \text{ mA};  V_{DS} = \text{V}_{GS};  \text{T}_j = 175 ^\circ\text{C}; \\ \text{see } \overline{\text{Figure 10}}$	0.8	-	-	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = -55 °C; see <u>Figure 10</u>	-	-	3.3	V
DSS	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.04	1	μA
		V <sub>DS</sub> = 55 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 175 °C	-	-	500	μA
GSS	gate leakage current	$V_{GS} = 20 \text{ V};  V_{DS} = 0 \text{ V};  T_j = 25 ^{\circ}\text{C}$	-	2	100	nA
		$V_{GS}$ = -20 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 90 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>	-	1.9	2.3	mΩ
		V <sub>GS</sub> = 5 V; I <sub>D</sub> = 90 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>	-	2.4	3.1	mΩ
		V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 90 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>	-	2.6	3.7	mΩ
		V <sub>GS</sub> 10 V; I <sub>D</sub> = 90 A; T <sub>j</sub> = 175 °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	-	5.7	mΩ
Dynamic ch	aracteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 180 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	253	-	nC
		$I_D = 180 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 5 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	140	-	nC
Q <sub>GS</sub>	gate-source charge	$I_D = 180 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 10 \text{ V};$	-	40	-	nC
Q <sub>GD</sub>	gate-drain charge	see <u>Figure 13</u> ; see <u>Figure 14</u>	-	79	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	12000	16000	pF
C <sub>oss</sub>	output capacitance	$T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 15}{\text{Figure } 15}$	-	1075	1290	pF
C <sub>rss</sub>	reverse transfer capacitance		-	730	1000	pF
d(on)	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 0.3 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	43	-	ns
r	rise time	$R_{G(ext)} = 10 \ \Omega$	-	206	-	ns
d(off)	turn-off delay time		-	412	-	ns
f	fall time		-	190	-	ns
Source-drai	in diode					
√ <sub>SD</sub>	source-drain voltage	$I_S = 80 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 16</u>	-	0.8	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 50 \text{ A}; \text{dI}_S/\text{dt} = -100 \text{ A}/\mu\text{s}; \text{V}_{GS} = 0 \text{ V};$	-	56	-	ns
Q <sub>r</sub>	recovered charge	V <sub>DS</sub> = 30 V; T <sub>j</sub> = 25 °C	_	115	_	nC

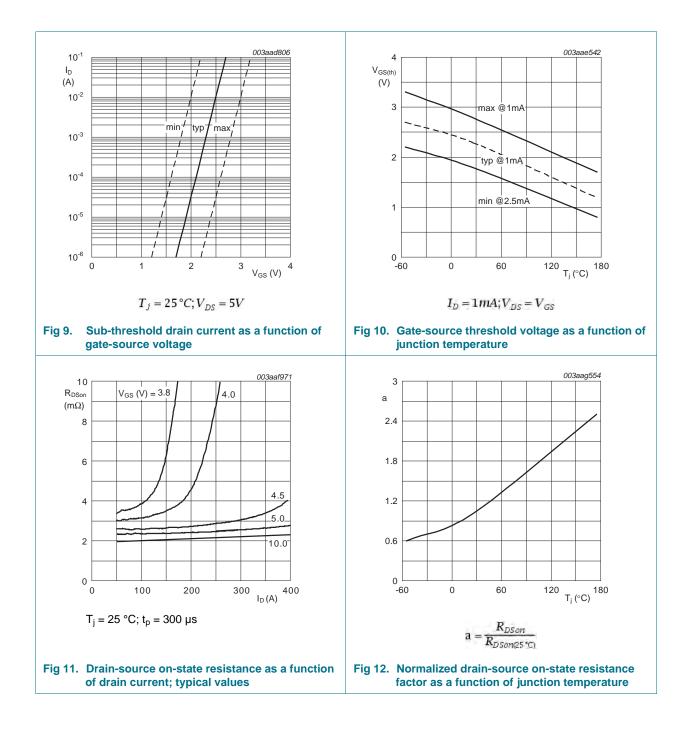
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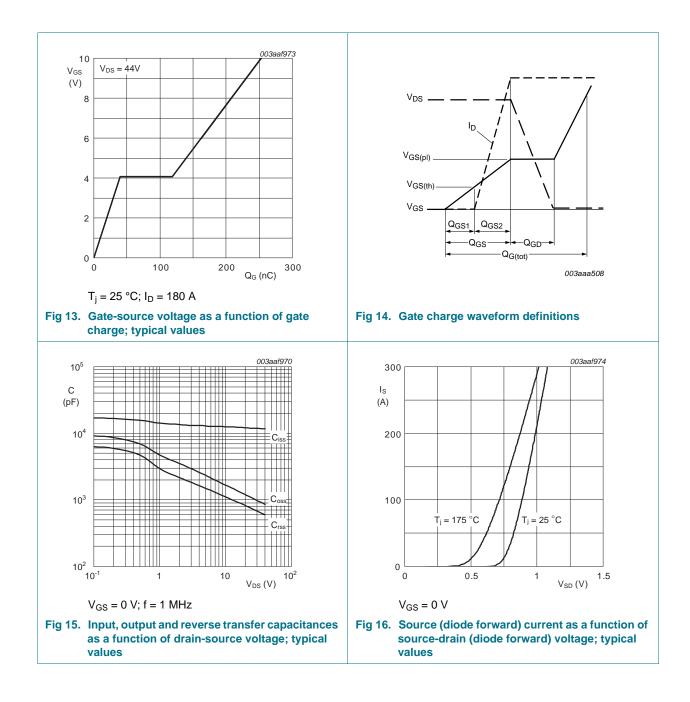
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### 7. Package outline

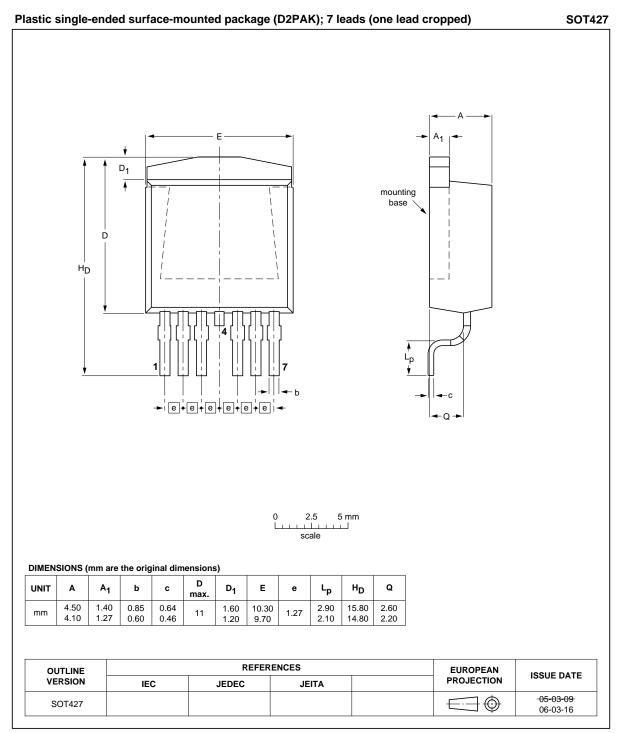


Fig 17. Package outline SOT427 (D2PAK)

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### 8. Revision history

Table 7. Revision h	nistory			
Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK6C2R1-55C v.3	20120118	Product data sheet	-	BUK6C2R1-55C v.2
Modifications:	<ul> <li>Status changed</li> </ul>	d from preliminary to produc	t.	
BUK6C2R1-55C v.2	20111221	Preliminary data sheet	t -	BUK6C2R1-55C v.1

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### 9. Legal information

#### 9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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